

Notic of References Cited	Application/Control No. 09/934,021	Applicant(s)/Patent Under Reexamination LEUNG ET AL.	
	Examiner John Pezzlo	Art Unit 2662	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,665,718 B1	12-2003	Chuah et al.	709/225
	B	US-			
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	K	US-			
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	M	US-			

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Reexamination
LEUNG ET AL.

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David Odland

Art Unit

2662

Page 1 of 1

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09/934,021Applicant(s)/Patent Under
Reexamination
LEUNG ET AL.Examiner
David OdlandArt Unit
2662

Page 1 of 1

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